

Agenda - Tuesday 6th November

	Academia and Industry Innovation Dowgate Room	Aerospace and Defence Bishopgate Room	Automotive Cripplegate Room	Semiconductor Aldgate Room	Building an Automated Test System Lower River Room	Developing an Automated Measurement System Auditorium
09:00	PLENARY KEYNOTE—FUTURE FASTER: TOMORROW'S TECHNOLOGIES MADE POSSIBLE TODAY					
10:15	Academia and Industry: Advancing Technology Together Dr Charlotte Nicolaou, National Instruments	A 40-Year Aerospace and Defence Test Veteran Remco Krul, National Instruments	The Automotive Industry Isn't Changing. It Already Has Daniel Riedelbauch, National Instruments, & Guest Presenter	Lowering the Cost of Test While Improving Time to Market With a Platform-Based Approach Joris Donders, National Instruments	What's New in LabVIEW 2018 and LabVIEW NXG Razvan Boldis and Andreas Palmstrøm, National Instruments	
10:45	BREAK AND EXHIBITION					
11:05	What's New From NI for Academia? Dr Charlotte Nicolaou, National Instruments	Testing Electronic and Electrical Systems Saab	Developing an Assurance Case Argument for Highly Automated Vehicles John Birch, HORIBA MIRA Ltd	InstrumentStudio™ Software for Interactive PXI Measurements George Tsalavoutis, National Instruments	What Makes a Good Test Software Framework? Phil Rawlings, Simplicity AI	Speed Up Software Development: The Increasing Power of Malleable VIs Ashley Nunn, National Instruments
11:50	Student Showcase: How Projects Can Enhance Graduate Skills Student Design Competition Finalists	Testing Earlier in the Life Cycle: Bridging the Gap Between Test and HIL Colin Freeman, Frazer-Nash Consultancy	How Do You Test an Electric Vehicle? Chris Garratt, Austin Consultants	NI Technology Deep Dive by NI Systems Engineering* <i>*Topic to be defined by customers</i> George Tsalavoutis, National Instruments	Importance of Abstraction and Standardisation in Automated Test Systems Jonathan Hobson, TBG Solutions	Uncovering the Mystery of Object- and Actor-Oriented Programming Tom McQuillan, Scientifica
12:35	LUNCH AND EXHIBITION					
13:25	Bridging the Hardware-Software Divide for Postgraduate Researchers Dr Gordon Flockhart, University of Strathclyde	Hardware-in-the-Loop Testing of Aerospace LRUs Mattias Engström, Syncore Technologies Anders Tunströmer, Saab	Testing Automated Driving Functions Using a Flexible XIL Approach Anirudda Reddy, IPG Automotive	Improving the Semiconductor Design-to-Test Flow George Zafiropoulos, National Instruments AWR Group, & Cadence Design Systems	Development Process of a Test System Ben Carruthers-Watt, Renishaw	Integrating Other Hardware with an NI DAQ System James McNally, Wiresmith Technology
14:10	Bridging the Valley of Death: Helping the UK Manufacturing Industry and University Research Work Together Morgan Williams, The Manufacturing Technology Centre	Designing and Deploying SIGINT and Electronic Warfare Systems Henrik Ulfhielm and Lars Hedlund, Novator Solutions	Open Hardware-in-the-Loop Platforms Frank Heidemann, SET	Increasing Efficiency in Semiconductor Post-Silicon Validation Engineering Ganesh Devaraj, Soliton Technologies	Power and Thermal Best Practices in Racked Test Systems Chris Jones, National Instruments	Validating Physical Systems With FlexLogger™ Andreas Jost, National Instruments
14:55	BREAK AND EXHIBITION					
15:15	Top Tips for Delivering a Successful Research Project: An Industry Perspective Austin Consultants	Challenges in Standardisation, Maintenance and Through-Life Support Erwan Lhermitte, Sphera UK	Utilising an Open HIL Platform to Contribute to a Multi-Vendor Application at Volvo Simon Schoutissen, Volvo Cars	Words of Wisdom: Lessons Learned From NI STS Deployments Sean Moynagh, Tessolve	Boosting Operational Efficiency With Distributed Systems Management Matthew Ferguson, National Instruments	Best Practices for Interfacing NI Products with MathWorks Software Dr Jeannie Falcon, National Instruments
16:00	PANEL DISCUSSION: Industry and Academia Collaboration Challenges	PANEL DISCUSSION: Differing Industries, Common Challenges—What Can Aerospace and Automotive Learn From Each Other?		Insight Into NI's Semiconductor Roadmap Priorities* <i>*NDA required</i> National Instruments	How to Collect and Analyze Test Data From Remote ATE Tero Leppänen, Etteplan	Why I Cringe When Everyone Wants Data in Excel James McNally, Wiresmith Technology
16:45–17:30	NETWORKING AND DRINKS RECEPTION					